

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/529,854	TANAKA, KOJIRO	
Examiner	Art Unit	
Bin Shen	1657	

SEARCHED					
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Class	Subclass	Date	Examiner		
NA	NA	6/6/2007	BS		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH N (INCLUDING SEARC		 )
	DATE	EXMR
STN-see printout.	6/6/2007	BS
Priority document checked.	6/6/2007	BS
Inventor name searched.	6/6/2007	BS
SEQ search: NA.	6/6/2007	BS
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